

August 2006

FDS2672

N-Channel UltraFET Trench[®] MOSFET 200V, 3.9A, 70m Ω

Features

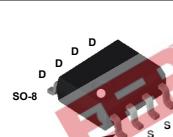
- Max $r_{DS(on)} = 70m\Omega$ at $V_{GS} = 10V$, $I_D = 3.9A$
- Max $r_{DS(on)} = 80m\Omega$ at $V_{GS} = 6V$, $I_D = 3.5A$
- Fast switching speed
- High performance trench technology for extremely low r_{DS(on)}
- RoHS compliant

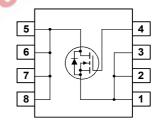
General Description

This single N-Channel MOSFET is produced using Fairchild Semiconductor's advanced UltraFET Trench® process that has been especially tailored to minimize the on-state resistance and yet maintain superior switching performance.

Application

■ DC-DC conversion





MOSFET Maximum Ratings T_A = 25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V_{DS}	Drain to Source Voltage		200	V
V_{GS}	Gate to Source Voltage		±20	V
	Drain Current -Continuous	(Note 1a)	3.9	^
ID	-Pulsed		50	— A
E _{AS}	Single Pulse Avalanche Energy	(Note 3)	37.5	mJ
П	Power Dissipation	(Note 1a)	2.5	W
P_{D}	Power Dissipation	(Note 1b)	1.0	VV
T _J , T _{STG}	Operating and Storage Temperature		-55 to 150	°C

Thermal Characteristics

R_{\thetaJC}	Thermal Resistance, Junction to Case	(Note 1)	25	
R_{\thetaJA}	Thermal Resistance, Junction to Ambient	(Note 1a)	50	°C/W
R _{e.IA}	Thermal Resistance, Junction to Ambient	(Note 1b)	125	

Package Marking and Ordering Information

Device Marking	Device	Reel Size	Tape Width	Quantity
FDS2672	FDS2672	13"	12mm	2500 units

Max Units

Min

Тур

Electrical Characteristics $T_J = 25^{\circ}C$ unless otherwise noted

Parameter

Off Characteristics						
BV_{DSS}	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	200			V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	I _D = 250μA, referenced to 25°C		206		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 160V, V _{GS} =0V V _{DS} = 160V, V _{GS} =0V T _J = 55°C			1 10	μA μA
I _{GSS}	Gate to Source Leakage Current	$V_{GS} = \pm 20V$			±100	nA

Test Conditions

On Characteristics (Note 2)

Symbol

V _{GS(th)}	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250 \mu A$	2	2.9	4	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	I _D = 250μA, referenced to 25°C		-11		mV/°C
		$V_{GS} = 10V, I_D = 3.9A$		59	70	
r _{DS(on)}	Drain to Source On Resistance	$V_{GS} = 6V, I_D = 3.5A$		63	80	mΩ
		$V_{GS} = 10V, I_D = 3.9A, T_J = 125^{\circ}C$		124	148	
g _{FS}	Forward Transcondductance	$V_{DS} = 10V, I_{D} = 3.9A$	-	15		S

Dynamic Characteristics

C _{iss}	Input Capacitance	V = 400V(1) = 0V	1905	2535	pF
C _{oss}	Output Capacitance	$V_{DS} = 100V, V_{GS} = 0V,$ f = 1MHz	100	135	pF
C _{rss}	Reverse Transfer Capacitance		30	45	pF
R _a	Gate Resistance	f = 1MHz	0.7		Ω

Switching Characteristics

$t_{d(on)}$	Turn-On Delay Time	10011	22	35	ns
t _r	Rise Time	V_{DD} = 100V, I_{D} = 3.9A - V_{GS} = 10V, R_{GEN} = 6Ω	10	20	ns
$t_{d(off)}$	Turn-Off Delay Time	V _{GS} = 10V, N _{GEN} = 052	35	56	ns
t _f	Fall Time		10	20	ns
$Q_{g(TOT)}$	Total Gate Charge at 10V		33	46	nC
Q_{gs}	Gate to Source Gate Charge	V _{DD} =100V I _D = 3.9A	11		nC
Q_{qd}	Gate to Drain "Miller" Charge		7		nC

Drain-Source Diode Characteristics

V_{SD}	Source to Drain Diode Voltage	V _{GS} = 0V, I _S = 3.9A	0.75	1.2	V
t _{rr}	Reverse Recovery Time	$I_F = 3.9A$, di/dt = 100A/ μ s	67	101	ns
Q _{rr}	Reverse Recovery Charge	I _F = 3.9A, di/dt = 100A/μs	179	269	nC

1. R_{θ,IA} is the sum of the junction-to-case and case-to- ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{θ,IC} is guaranteed by design while R_{θ,CA} is determined by the user's board design.



a) 50°C/W (10 sec) 62.5°C/W steady state when mounted on a 1in² pad of 2 oz copper



b) 125°C/W when mounted on a minimum pad .

- 2: Pulse Test: Pulse Width < 300 us, Duty Cycle < 2.0%. 3: Starting $T_J = 25^{\circ}C$, L = 3mH, $I_{AS} = 5A$, $V_{DD} = 100V$, $V_{GS} = 10V$



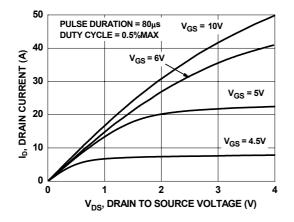


Figure 1. On Region Characteristics

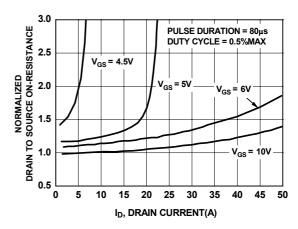


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

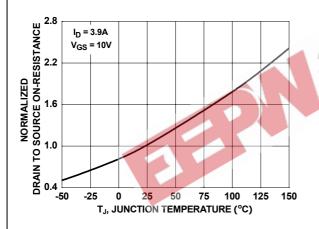


Figure 3. Normalized On Resistance vs Junction Temperature

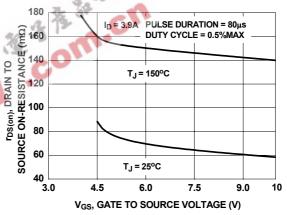


Figure 4. On-Resistance vs Gate to Source Voltage

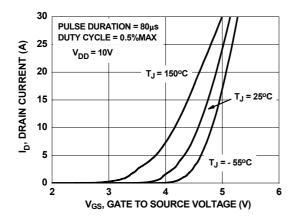


Figure 5. Transfer Characteristics

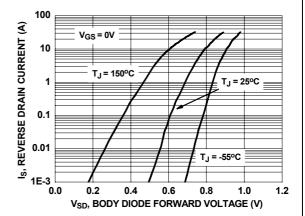
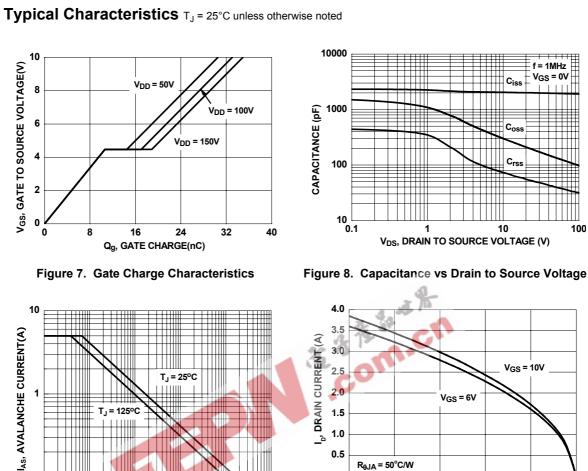


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

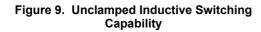
100

V_{GS} = 0V



100

1000



t_{AV}, TIME IN AVALANCHE(ms)

 $T_{\rm J} = 125^{\rm o}C$

0.1 — 0.01

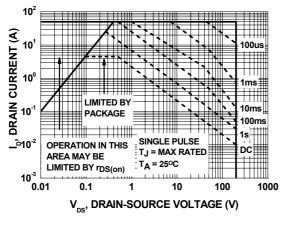


Figure 11. Forward Bias Safe Operating Area

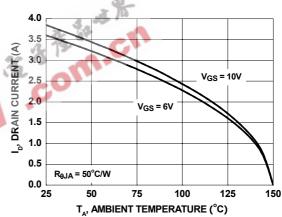


Figure 10. Ambient Continuous Drain Current vs **Case Temperature**

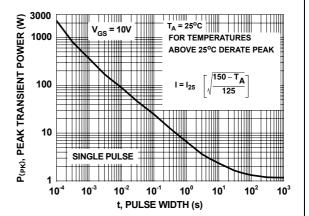
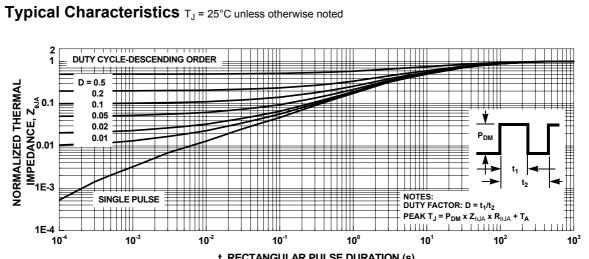
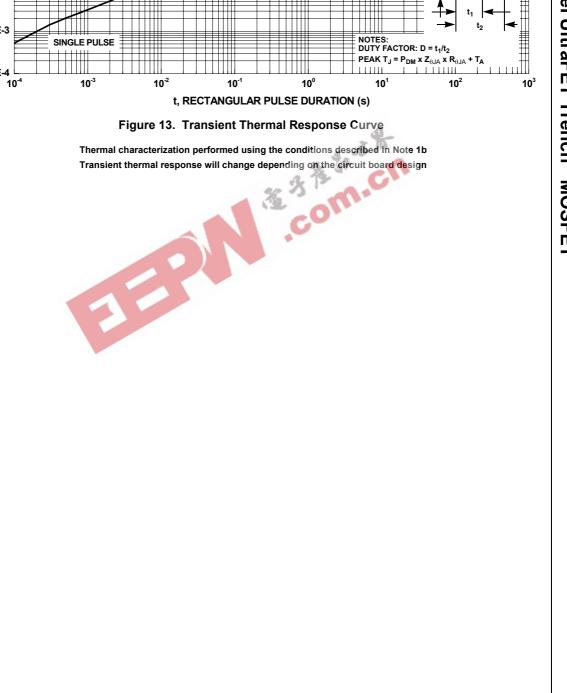


Figure 12. Single Pulse Maximum Power Dissipation





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